

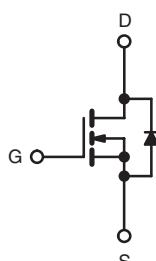
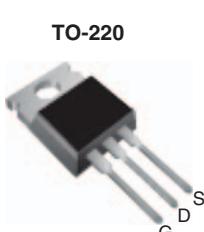


KERSEMI

IRFB17N60K, SiHFB17N60K

## Power MOSFET

PRODUCT SUMMARY	
V <sub>DS</sub> (V)	600
R <sub>D(on)</sub> (Ω)	V <sub>GS</sub> = 10 V      0.35
Q <sub>g</sub> (Max.) (nC)	99
Q <sub>gs</sub> (nC)	32
Q <sub>gd</sub> (nC)	47
Configuration	Single



N-Channel MOSFET

RoHS\*  
COMPLIANT

### FEATURES

- Smaller TO-220 Package
- Low Gate Charge Q<sub>g</sub> Results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Lead (Pb)-free Available

### APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits

ORDERING INFORMATION	
Package	TO-220
Lead (Pb)-free	IRFB17N60KPbF SiHFB17N60K-E3
SnPb	IRFB17N60K SiHFB17N60K

ABSOLUTE MAXIMUM RATINGS T <sub>C</sub> = 25 °C, unless otherwise noted				
PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage		V <sub>DS</sub>	600	
Gate-Source Voltage		V <sub>GS</sub>	± 30	V
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C	I <sub>D</sub>	A
		T <sub>C</sub> = 100 °C	11	
Pulsed Drain Current <sup>a</sup>		I <sub>DM</sub>	68	
Linear Derating Factor			2.7	W/°C
Single Pulse Avalanche Energy <sup>b</sup>		E <sub>AS</sub>	330	mJ
Repetitive Avalanche Current <sup>a</sup>		I <sub>AR</sub>	17	A
Repetitive Avalanche Energy <sup>a</sup>		E <sub>AR</sub>	34	mJ
Maximum Power Dissipation	T <sub>C</sub> = 25 °C	P <sub>D</sub>	340	W
Peak Diode Recovery dV/dt <sup>c</sup>		dV/dt	11	V/ns
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s		300 <sup>d</sup>	
Mounting Torque	6-32 or M3 screw		10	N

#### Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- Starting T<sub>J</sub> = 25 °C, L = 2.3 mH, R<sub>G</sub> = 25 Ω, I<sub>AS</sub> = 17 A (see fig. 12).
- I<sub>SD</sub> ≤ 17 A, dI/dt ≤ 380 A/μs, V<sub>DD</sub> ≤ V<sub>DS</sub>, T<sub>J</sub> ≤ 150 °C.
- 1.6 mm from case.

**THERMAL RESISTANCE RATINGS**

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	$R_{thJA}$	-	58	°C/W
Case-to-Sink, Flat, Greased Surface	$R_{thCS}$	0.50	-	
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	0.37	

**SPECIFICATIONS**  $T_J = 25^\circ\text{C}$ , unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
<b>Static</b>							
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}$	$I_D = 250 \mu\text{A}$	600	-	-	V
$V_{DS}$ Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25^\circ\text{C}$ , $I_D = 1 \text{ mA}$		-	600	-	mV/°C
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$	$I_D = 250 \mu\text{A}$	3.0	-	5.0	V
Gate-Source Leakage	$I_{GSS}$	$V_{GS} = \pm 30 \text{ V}$		-	-	$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 600 \text{ V}$ , $V_{GS} = 0 \text{ V}$		-	-	50	μA
		$V_{DS} = 480 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $T_J = 125^\circ\text{C}$		-	-	250	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 10 \text{ A}^b$	-	0.35	0.42	Ω
Forward Transconductance	$g_{fs}$	$V_{DS} = 50 \text{ V}$ , $I_D = 10 \text{ A}$		5.9	-	-	S
<b>Dynamic</b>							
Input Capacitance	$C_{iss}$	$V_{GS} = 0 \text{ V}$ , $V_{DS} = 25 \text{ V}$ , $f = 1.0 \text{ MHz}$ , see fig. 5		-	2700	-	pF
Output Capacitance	$C_{oss}$			-	240	-	
Reverse Transfer Capacitance	$C_{rss}$			-	21	-	
Output Capacitance	$C_{oss}$	$V_{GS} = 0 \text{ V}$	$V_{DS} = 1.0 \text{ V}$ , $f = 1.0 \text{ MHz}$	-	2950	-	
		$V_{GS} = 0 \text{ V}$	$V_{DS} = 480 \text{ V}$ , $f = 1.0 \text{ MHz}$	-	67	-	
Effective Output Capacitance	$C_{oss eff.}$	$V_{GS} = 0 \text{ V}$	$V_{DS} = 0 \text{ V}$ to $480 \text{ V}$	-	120	-	
Total Gate Charge	$Q_g$	$V_{GS} = 10 \text{ V}$	$I_D = 17 \text{ A}$ , $V_{DS} = 480 \text{ V}$ see fig. 6 and 13	-	-	99	nC
Gate-Source Charge	$Q_{gs}$			-	-	32	
Gate-Drain Charge	$Q_{gd}$			-	-	47	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 300 \text{ V}$ , $I_D = 17 \text{ A}$ , $R_G = 7.5 \Omega$ , $V_{GS} = 10 \text{ V}$ , see fig. 10 <sup>b</sup>		-	25	-	ns
Rise Time	$t_r$			-	82	-	
Turn-Off Delay Time	$t_{d(off)}$			-	38	-	
Fall Time	$t_f$			-	32	-	
<b>Drain-Source Body Diode Characteristics</b>							
Continuous Source-Drain Diode Current	$I_S$	MOSFET symbol showing the integral reverse p - n junction diode		-	-	17	A
Pulsed Diode Forward Current <sup>a</sup>	$I_{SM}$			-	-	68	
Body Diode Voltage	$V_{SD}$	$T_J = 25^\circ\text{C}$ , $I_S = 17 \text{ A}$ , $V_{GS} = 0 \text{ V}^b$		-	-	1.5	V
Body Diode Reverse Recovery Time	$t_{rr}$	$T_J = 25^\circ\text{C}$ , $I_F = 17 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	520	780	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$			-	5620	8430	nC
Body Diode Reverse Recovery Time	$t_{rr}$	$T_J = 125^\circ\text{C}$ , $I_F = 17 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	580	870	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$			-	6470	9700	nC
Forward Turn-On Time	$t_{on}$	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_D$ )					

**Notes**

- a. Repetitive rating, pulse width limited by max. junction temperature.  
b. Pulse width  $\leq 300 \mu\text{s}$ ; duty cycle  $\leq 2\%$ .



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**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted

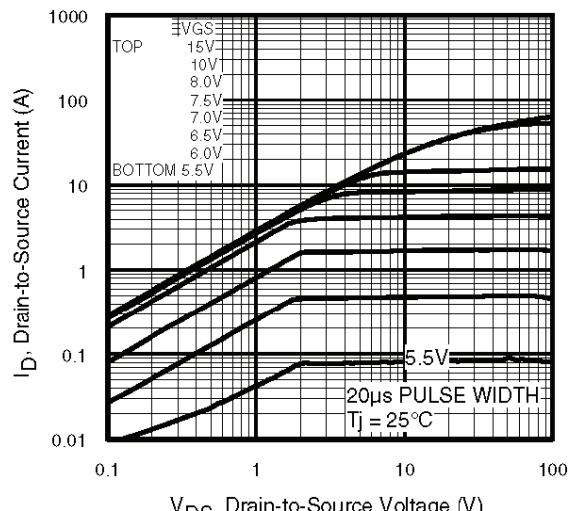


Fig. 1 - Typical Output Characteristics

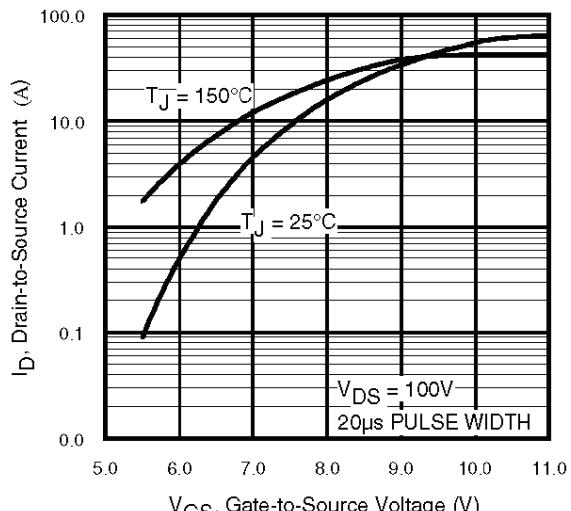


Fig. 3 - Typical Transfer Characteristics

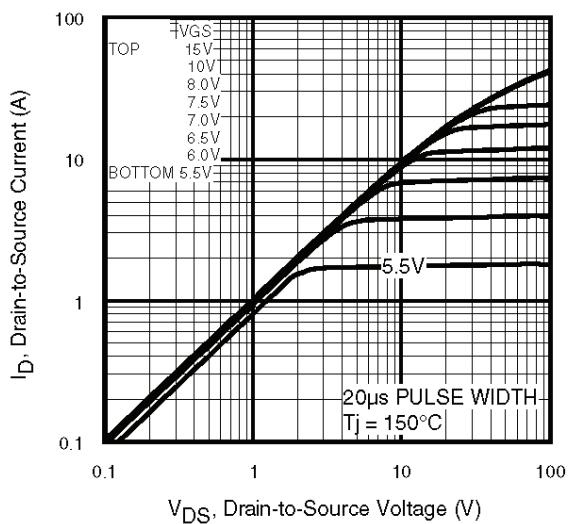


Fig. 2 - Typical Output Characteristics

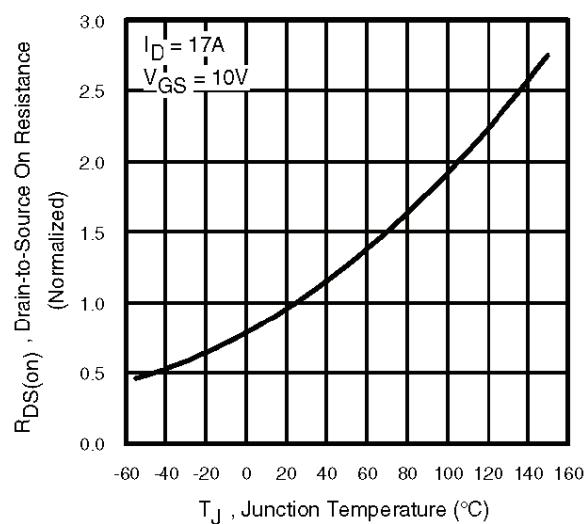


Fig. 4 - Normalized On-Resistance vs. Temperature

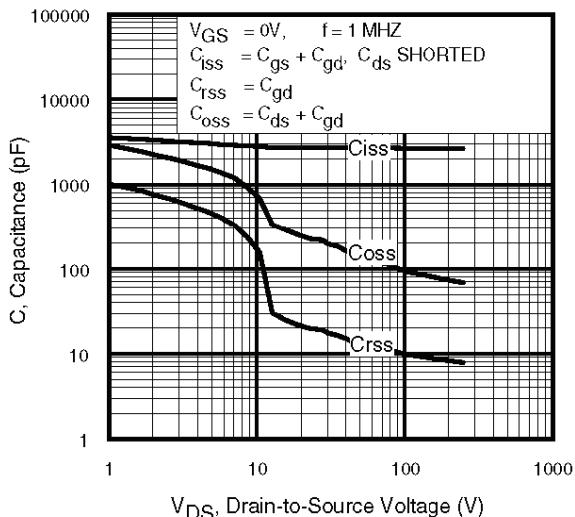


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

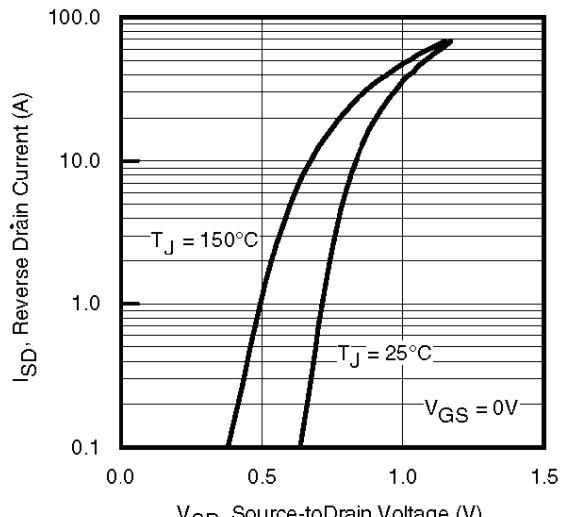


Fig. 7 - Typical Source-Drain Diode Forward Voltage

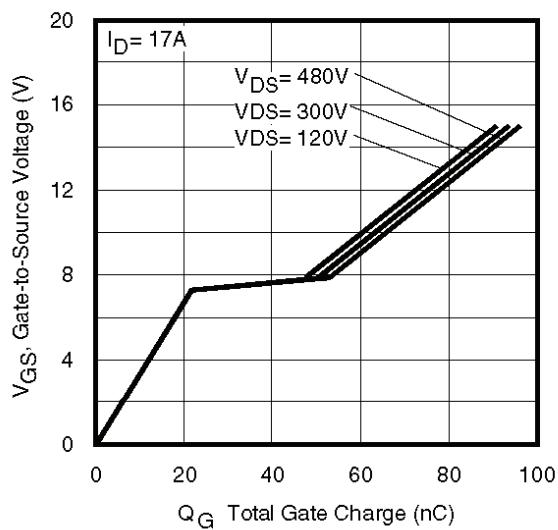


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

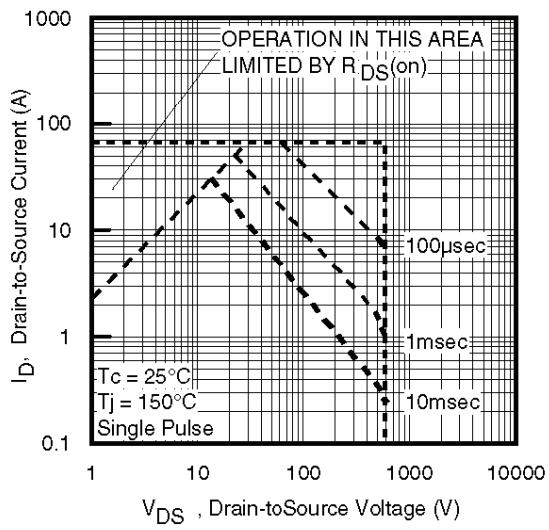


Fig. 8 - Maximum Safe Operating Area



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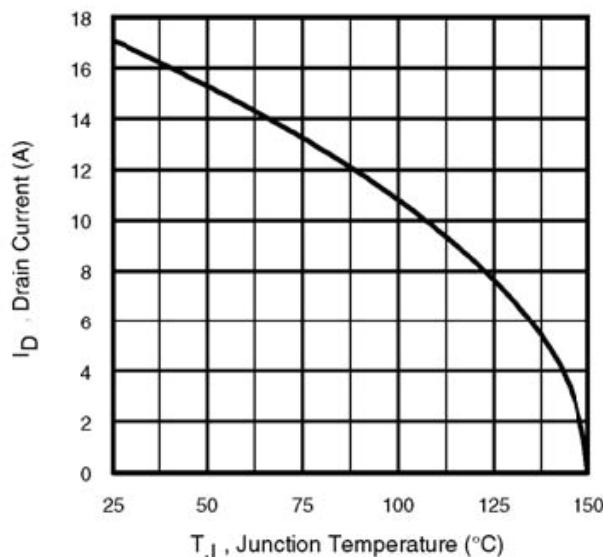


Fig. 9 - Maximum Drain Current vs. Case Temperature

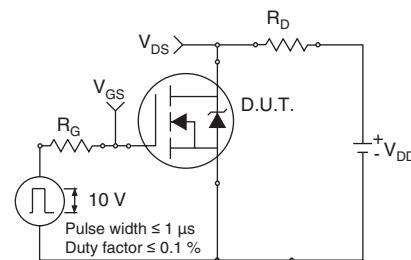


Fig. 10a - Switching Time Test Circuit

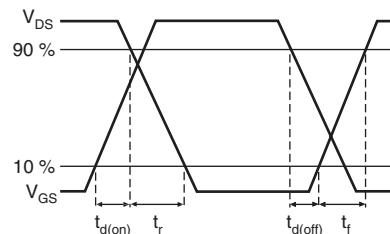


Fig. 10b - Switching Time Waveforms

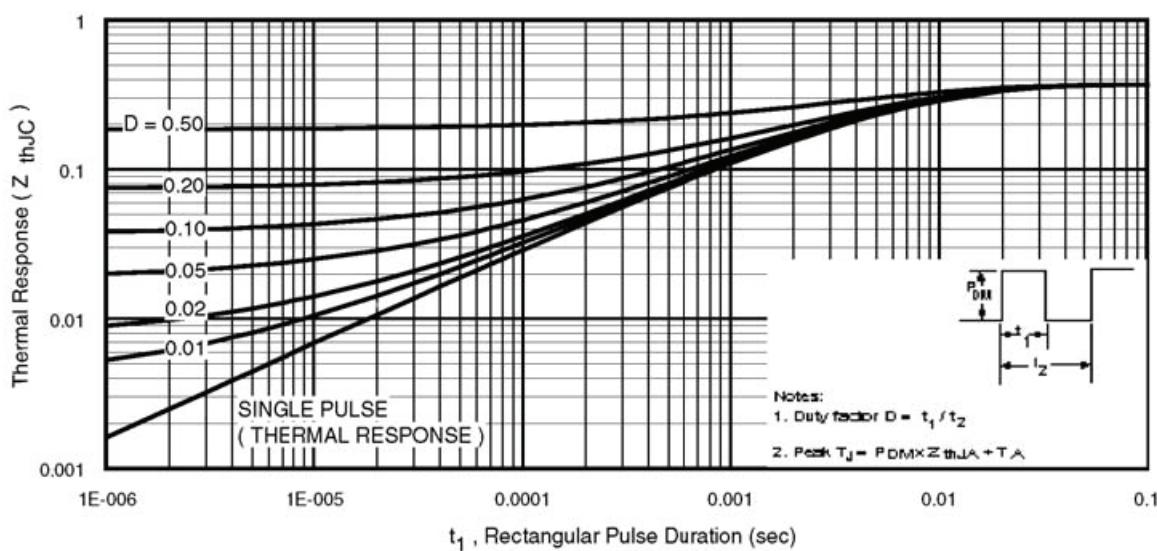


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

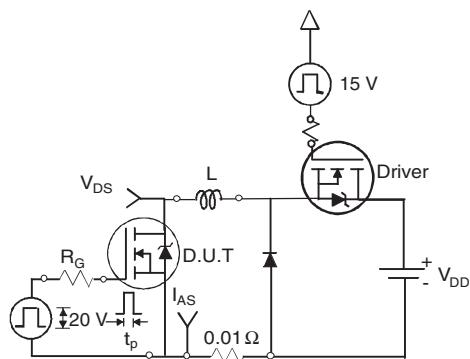


Fig. 12a - Unclamped Inductive Test Circuit

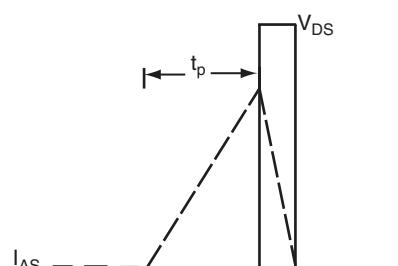
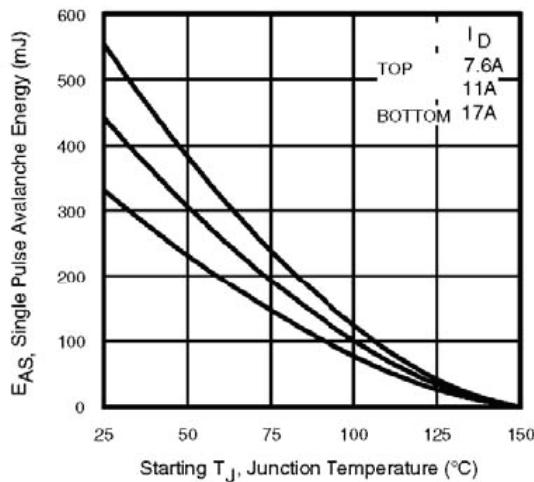
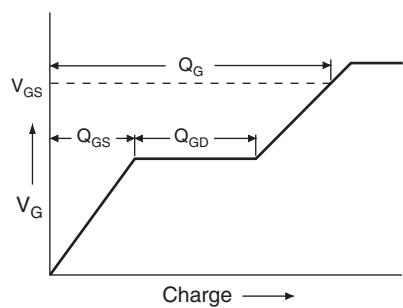


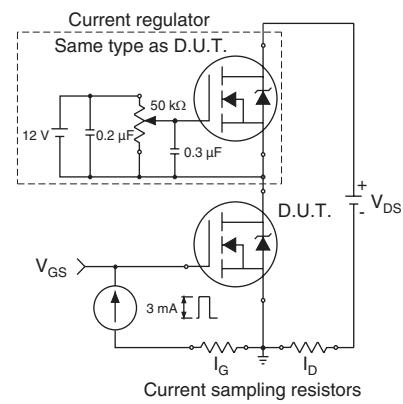
Fig. 12b - Unclamped Inductive Waveforms



**Fig. 12c - Maximum Avalanche Energy vs. Drain Current**



**Fig. 13a - Basic Gate Charge Waveform**



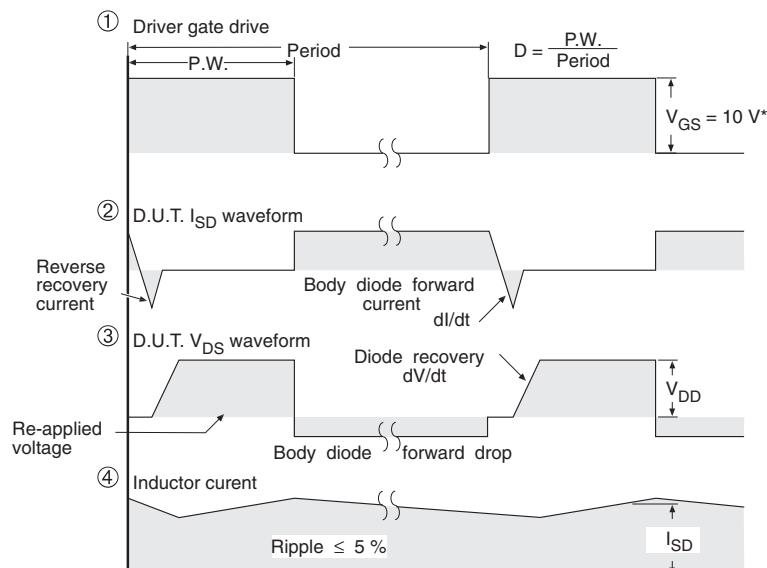
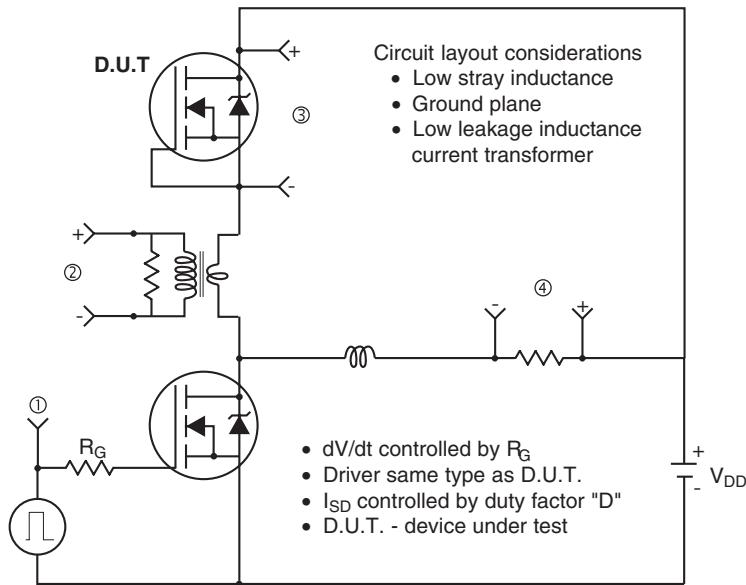
**Fig. 13b - Gate Charge Test Circuit**



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### Peak Diode Recovery dV/dt Test Circuit



\*  $V_{GS} = 5 \text{ V}$  for logic level devices

Fig. 14 - For N-Channel